2.5 V/3.3 V Any Level Positive Input to -2.5 V/-3.3 V LVNECL Output Translator

Description

The NB100LVEP91 is a triple any level positive input to NECL output translator. The device accepts LVPECL, LVTTL, LVCMOS, HSTL, CML or LVDS signals, and translates them to differential LVNECL output signals (-2.5 V/-3.3 V).

To accomplish the level translation the LVEP91 requires three power rails. The V_{CC} pins should be connected to the positive power supply, and the V_{EE} pin should be connected to the negative power supply. The GND pins are connected to the system ground plane. Both V_{EE} and V_{CC} should be bypassed to ground via 0.01 μF capacitors.

Under open input conditions, the \overline{D} input will be biased at $V_{CC}/2$ and the D input will be pulled to GND. These conditions will force the Q outputs to a low state, and Q outputs to a high state, which will ensure stability.

The V_{BB} pin, an internally generated voltage supply, is available to this device only. For single-ended input conditions, the unused differential input is connected to V_{BB} as a switching reference voltage. V_{BB} may also rebias AC coupled inputs. When used, decouple V_{BB} and V_{CC} via a $0.01~\mu F$ capacitor and limit current sourcing or sinking to 0.5~mA. When not used, V_{BB} should be left open.

Features

- Maximum Input Clock Frequency > 2.0 GHz Typical
- Maximum Input Data Rate > 2.0 Gb/s Typical
- 500 ps Typical Propagation Delay
- Operating Range:
 - $V_{CC} = 2.375 \text{ V}$ to 3.8 V; $V_{EE} = -2.375 \text{ V}$ to -3.8 V; GND = 0 V
- Q Output will Default LOW with Inputs Open or at GND
- These Devices are Pb-Free, Halogen Free and are RoHS Compliant



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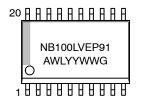


SOIC-20 WB DW SUFFIX CASE 751D-05



QFN-24 MN SUFFIX CASE 485L-01

MARKING DIAGRAMS*





A = Assembly Location

WL, L = Wafer Lot YY. Y = Year

YY, Y = Year

WW, W = Work Week
G or ■ = Pb-Free Package

(Note: Microdot may be in either location)

*For additional marking information, refer to Application Note <u>AND8002/D</u>.

ORDERING INFORMATION

Device	Package	Shipping [†]
MB100LVEP91DWG	SOIC-20 WB (Pb-Free)	38 Units/Tube
MB100LVEP91DWR2G	SOIC-20 WB (Pb-Free)	1000/Tape & Reel
MB100LVEP91MNG	QFN-24 (Pb-Free)	92 Units/Tube
MB100LVEP91MNR2G	QFN-24 (Pb-Free)	3000/Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

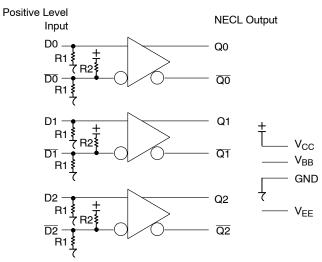


Figure 1. Logic Diagram

Table 1. PIN DESCRIPTION

ı	Pin			Defects	
SOIC	QFN	Name	I/O	Default State	Description
1, 20	3, 4, 12	V _{CC}	-	-	Positive Supply Voltage. All $V_{\rm CC}$ Pins must be Externally Connected to Power Supply to Guarantee Proper Operation.
10	15, 16	V _{EE}	-	-	Negative Supply Voltage. All V_{EE} Pins must be Externally Connected to Power Supply to Guarantee Proper Operation.
14, 17	19, 20, 23, 24	GND	-	-	Ground.
4, 7	7, 11	V_{BB}	-	_	ECL Reference Voltage Output
2, 5, 8	5, 8, 13	D[0:2]	LVPECL, LVDS, LVTTL, LVCMOS, CML, HSTL Input	Low	Non-inverted Differential Inputs [0:2]. Internal 75 k Ω to GND.
3, 6, 9	6, 9, 14	D[0:2]	LVPECL, LVDS, LVTTL,LVCMOS, CML, HSTL Input	High	Inverted Differential Inputs [0:2]. Internal 75 k Ω to GND and 75 k Ω to V _{CC} . When Inputs are Left Open They Default to (V _{CC} – GND) / 2.
19,16,13	2, 22, 18	Q[0:2]	LVNECL Output	-	Non-inverted Differential Outputs [0:2]. Typically Terminated with 50 Ω to V $_{TT}$ = V $_{CC}$ $-$ 2 V
18,15,12	1, 21, 17	Q[0:2]	LVNECL Output	-	Inverted Differential Outputs [0:2]. Typically Terminated with 50 Ω to V_{TT} = V_{CC} – 2 V
11	10	NC	-	-	No Connect. The NC Pin is NOT Electrically Connected to the Die and may Safely be Connected to Any Voltage from V_{EE} to V_{CC} .
N/A	-	EP	-		Exposed Pad. (Note 1)

The thermally conductive exposed pad on the package bottom (see case drawing) must be attached to a heat sinking conduit and may only be electrically connected to V_{EE} (not GND).

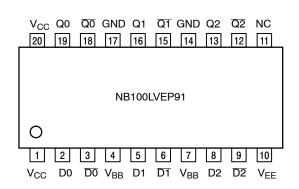


Figure 2. SOIC-20 WB Lead Pinout (Top View)*

*All V_{CC} , V_{EE} and GND pins must be externally connected to a power supply.

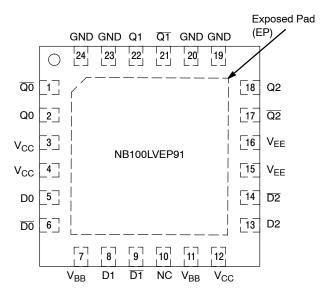


Figure 3. QFN-24 Lead Pinout (Top View)*

*All V_{CC}, V_{EE} and GND pins must be externally connected to a power supply. The thermally conductive exposed pad on the package bottom (see case drawing) must be attached to a sufficient heat-sinking conduit and may only be electronically connected to V_{EE} (not GND).

Table 2. ATTRIBUTES

Characteristics	Value				
Internal Input Pulldown Resistor (R1)	75 kΩ				
Internal Input Pullup Resistor (R2)	75 kΩ				
ESD Protection Human Body Model Machine Model Charged Device Model	> 2 kV > 150 V > 2 kV				
Moisture Sensitivity (Note 1)	Pb-Free Pkg				
SOIC-20 WB QFN-24	Level 3 Level 1				
Flammability Rating Oxygen Index: 28 to 34	UL 94 V-0 @ 0.125 in				
Transistor Count	446 Devices				
Meets or exceeds JEDEC Spec EIA/JESD78 IC Latchup Test					

^{1.} For additional information, see Application Note AND8003/D.

Table 3. MAXIMUM RATINGS

Symbol	Parameter	Condition 1	Condition 2	Rating	Unit
V _{CC}	Positive Power Supply	GND = 0 V		3.8 to 0	V
V _{EE}	Negative Power Supply	GND = 0 V		-3.8 to 0	V
VI	Positive Input Voltage	GND = 0 V	$V_{I} \leq V_{CC}$	3.8 to 0	٧
V _{OP}	Operating Voltage	GND = 0 V	V _{CC} - V _{EE}	7.6 to 0	٧
I _{out}	Output Current	Continuous Surge		50 100	mA
I_{BB}	PECL V _{BB} Sink/Source			± 0.5	mA
T _A	Operating Temperature Range			-40 to +85	°C
T _{stg}	Storage Temperature Range			-65 to +150	°C
$\theta_{\sf JA}$	Thermal Resistance (Junction-to-Ambient) JESD 51-3 (1S-Single Layer Test Board)	0 lfpm 500 lfpm	SOIC-20 WB	90 60	°C/W
$\theta_{\sf JA}$	Thermal Resistance (Junction-to-Ambient) JESD 51-6 (2S2P Multilayer Test Board) with Filled Thermal Vias	0 lfpm 500 lfpm	QFN-24	37 32	°C/W
θЈС	Thermal Resistance (Junction-to-Case)	Standard Board	SOIC-20 WB QFN-24	30 to 35 11	°C/W
T _{sol}	Wave Solder (Pb-Free)			225	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

Table 4. DC CHARACTERISTICS POSITIVE INPUTS ($V_{CC} = 2.5 \text{ V}$, $V_{EE} = -2.375 \text{ to } -3.8 \text{ V}$, GND = 0 V (Note 1))

			-40°C			25°C			85°C			
Symbol	Characteristic	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit	
I _{CC}	Positive Power Supply Current	10	14	20	10	14	20	10	14	20	mA	
V _{IH}	Input HIGH Voltage (Single-Ended)	1335		V_{CC}	1335		V_{CC}	1335		V _{CC}	mV	
V_{IL}	Input LOW Voltage (Single-Ended)	GND		875	GND		875	GND		875	mV	
V _{IHCMR}	Input HIGH Voltage Common Mode Range (Differential Configuration) (Note 2)	0		2.5	0		2.5	0		2.5	٧	
I _{IH}	Input HIGH Current (@ V _{IH})			150			150			150	μΑ	
I _{IL}	Input LOW Current (@ V _{IL}) D D	0.5 -150			0.5 -150			0.5 -150			μΑ	

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

- 1. Input parameters vary 1:1 with V_{CC} . V_{CC} can vary +1.3 V / -0.125 V. 2. V_{IHCMR} min varies 1:1 with GND. V_{IHCMR} max varies 1:1 with V_{CC} .

Table 5. DC CHARACTERISTICS POSITIVE INPUT (V_{CC} = 3.3 V; V_{EE} = -2.375 V to -3.8 V; GND = 0 V (Note 1))

			-40°C			25°C			85°C			
Symbol	Characteristic	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit	
I _{CC}	Positive Power Supply Current	10	16	24	10	16	24	10	16	24	mA	
V _{IH}	Input HIGH Voltage (Single-Ended)	2135		V_{CC}	2135		V_{CC}	2135		V_{CC}	mV	
V _{IL}	Input LOW Voltage (Single-Ended)	GND		1675	GND		1675	GND		1675	mV	
V _{BB}	PECL Output Voltage Reference	1775	1875	1975	1775	1875	1975	1775	1875	1975	mV	
V _{IHCMR}	Input HIGH Voltage Common Mode Range (Differential Configuration) (Note 2)	0		3.3	0		3.3	0		3.3	V	
I _{IH}	Input HIGH Current (@ V _{IH})			150			150			150	μΑ	
I _{IL}	Input LOW Current (@ V _{IL}) D D	0.5 -150			0.5 -150			0.5 -150			μΑ	

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

- 1. Input parameters vary 1:1 with $V_{CC}.\ V_{CC}$ can vary +0.5 / -0.925 V.
- 2. V_{IHCMR} min varies 1:1 with GND. V_{IHCMR} max varies 1:1 with V_{CC} .

Table 6. DC CHARACTERISTICS NECL OUTPUT (V_{CC} = 2.375 V to 3.8 V; V_{EE} = -2.375 V to -3.8 V; GND = 0 V (Note 1))

		−40°C			25°C						
Symbol	Characteristic	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
I _{EE}	Negative Power Supply Current	40	50	60	38	50	68	38	50	68	mA
V _{OH}	Output HIGH Voltage (Note 2)	-1145	-1020	-895	-1145	-1020	-895	-1145	-1020	-895	mV
V _{OL}	Output LOW Voltage (Note 2)	-1945	-1770	-1600	-1945	-1770	-1600	-1945	-1770	-1600	mV

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

- 1. Output parameters vary 1:1 with GND.
- 2. All loading with 50 Ω resistor to GND 2.0 V.

Table 7. AC CHARACTERISTICS ($V_{CC} = 2.375 \text{ V to } 3.8 \text{ V}$; $V_{EE} = -2.375 \text{ V to } -3.8 \text{ V}$; GND = 0 V)

		-40°C		25°C							
Symbol	Characteristic	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
V _{OUTPP}	Output Voltage Amplitude (Figure 4) (Note 1) $f_{in} \perp \ \ $ 1.0 GHz $f_{in} \perp \ \ \ $ 1.5 GHz $f_{in} \perp \ \ \ $ 2.0 GHz	575 525 300	800 750 600		600 525 250	800 750 550		550 400 150	800 750 500		mV
t _{PLH} t _{PHL0}	Propagation Delay Differential D to Q Single-Ended	375 300	500 450	600 650	375 300	500 450	600 675	400 300	550 500	650 750	ps
t _{SKEW}	Pulse Skew (Note 2) Output-to-Output (Note 3) Part-to-Part (Diff) (Note 3)		15 25 50	75 95 125		15 30 50	75 105 125		15 30 70	80 105 150	ps
t _{JITTER}	RMS Random Clock Jitter (Note 4) f _{in} = 2.0 GHz Peak-to-Peak Data Dependant Jitter (Note 5) f _{in} = 2.0 Gb/s		0.5 20	2.0		0.5 20	2.0		0.5 20	2.0	ps
V _{INPP}	Input Voltage Swing (Differential Configuration) (Note 6)	200	800	1200	200	800	1200	200	800	1200	mV
t _r , t _f	Output Rise/Fall Times @ 50 MHz (20% – 80%) Q, Q	75	150	250	75	150	250	75	150	275	ps

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

- 1. Measured using a 750 mV source, 50% duty cycle clock source. All loading with 50 Ω to GND 2.0 V. Input edge rates 150 ps (20% 80%).
- 2. Pulse Skew = |tplh tphl
- 3. Skews are valid across specified voltage range, part-to-part skew is for a given temperature.
- RMS Jitter with 50% Duty Cycle Input Clock Signal.
 Peak-to-Peak Jitter with input NRZ PRBS 2³¹⁻¹ at 2.0 Gb/s.
- 6. Input voltage swing is a single-ended measurement operating in differential mode. The device has a DC gain of ≈ 50.

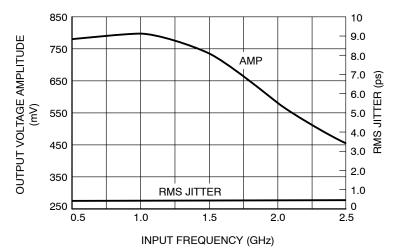


Figure 4. Output Voltage Amplitude (V_{OUTPP}) / RMS Jitter vs. Input Frequency (fin) at Ambient Temperature (Typical)

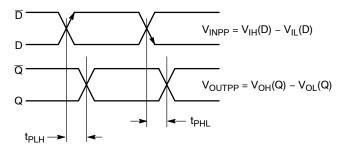


Figure 5. AC Reference Measurement

Application Information

All NB100LVEP91 inputs can accept LVPECL, LVTTL, LVCMOS, HSTL, CML, or LVDS signal levels. The limitations for differential input signal (LVDS, HSTL, LVPECL, or CML) are the minimum input swing of 150 mV

LVPECL LVEP91 Driver 50 Ω ≥ 50 Ω

Figure 6. Standard LVPECL Interface

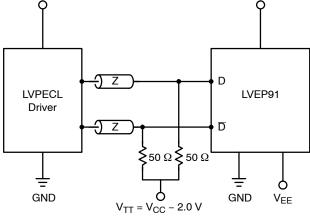


Figure 7. Standard LVDS Interface V_{CC} **≥**50 Ω **≥** 50 Ω () Z CML LVEP91 Driver D 7

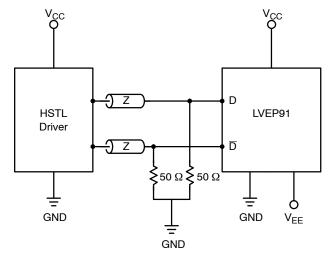


Figure 8. Standard HSTL Interface

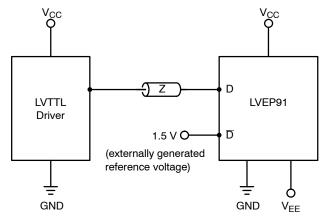
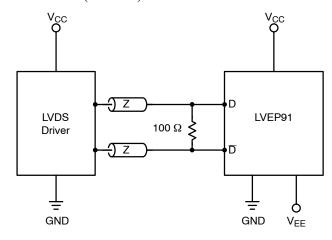


Figure 10. Standard LVTTL Interface

and the maximum input swing of 3.0 V. Within these conditions, the input voltage can range from V_{CC} to GND. Examples interfaces are illustrated below in a 50 Ω environment ($Z = 50 \Omega$)



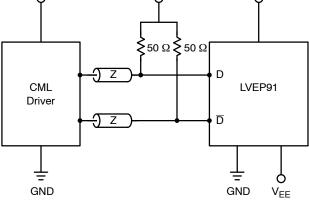


Figure 9. Standard 50 Ω Load CML Interface

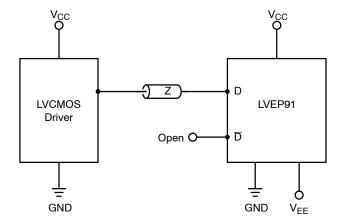


Figure 11. Standard LVCMOS Interface $(\overline{D}$ Will Default to $V_{CC}/2$ When Left Open. A Reference Voltage of V_{CC}/2 Should be Applied to D Input, if \overline{D} is Interfaced to CMOS Signals.)

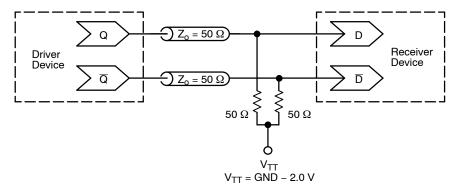


Figure 12. Typical Termination for Output Driver and Device Evaluation (See Application Note <u>AND8020/D</u> – Termination of ECL Logic Devices.)

Resource Reference of Application Notes

AN1405/D - ECL Clock Distribution Techniques

AN1406/D - Designing with PECL (ECL at +5.0 V)

AN1503/D - ECLinPS™ I/O SPiCE Modeling Kit

AN1504/D - Metastability and the ECLinPS Family

AN1568/D - Interfacing Between LVDS and ECL

AN1672/D - The ECL Translator Guide

AND8001/D - Odd Number Counters Design

AND8002/D - Marking and Date Codes

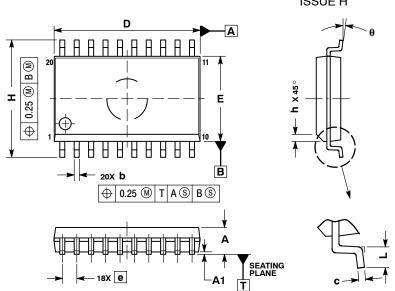
AND8020/D - Termination of ECL Logic Devices

AND8066/D - Interfacing with ECLinPS

AND8090/D - AC Characteristics of ECL Devices

PACKAGE DIMENSIONS

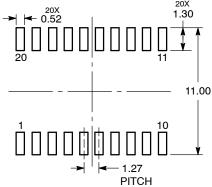
SOIC-20 WB CASE 751D-05 **ISSUE H**



- NOTES:
 1. DIMENSIONS ARE IN MILLIMETERS.
 2. INTERPRET DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994.
 3. DIMENSIONS D AND E DO NOT INCLUDE MOLD PROTRUSION.
 4. MAXIMUM MOLD PROTRUSION 0.15 PER SIDE.
 5. DIMENSION B DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE PROTRUSION SHALL BE 0.13 TOTAL IN EXCESS OF B DIMENSION AT MAXIMUM MATERIAL CONDITION.

	MILLIMETERS								
DIM	MIN	MAX							
Α	2.35	2.65							
A1	0.10	0.25							
b	0.35	0.49							
С	0.23	0.32							
D	12.65	12.95							
Е	7.40	7.60							
е	1.27	BSC							
Н	10.05	10.55							
h	0.25	0.75							
L	0.50	0.90							
θ	0 °	7 °							

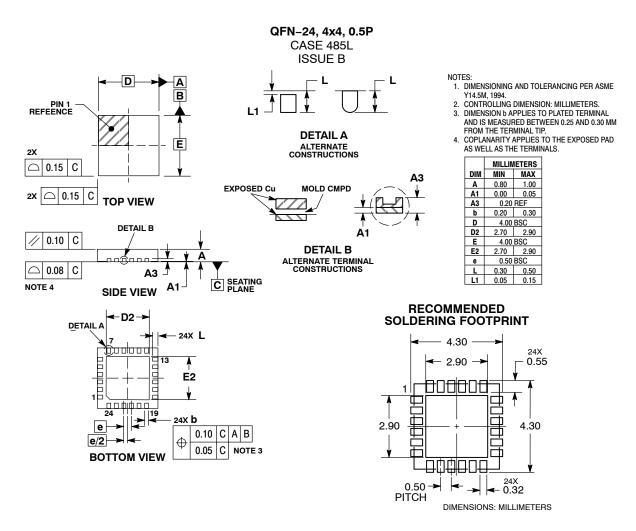
RECOMMENDED SOLDERING FOOTPRINT*



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^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, <u>SOLDERRM/D</u>.

PACKAGE DIMENSIONS



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